

 Search Result - Print Format[< Back to Previous Page](#)

**Key:** IEEE JNL = IEEE Journal or Magazine, IEE JNL = IEE Journal or Magazine, IEEE CNF = IEEE Conference, IEE CNF = IEE Conference, IEEE STD = IEEE Standard

**1. Minimal test configurations for FPGA local interconnects**

Sun, X.; Xu, J.; Alimohammad, A.; Trouborst, P.;  
Electrical and Computer Engineering, 2002. IEEE CCECE 2002. Canadian Conference on  
Volume 1, 12-15 May 2002 Page(s):427 - 432 vol.1

IEEE CNF

**2. Design and implementation of a parity-based BIST scheme for FPGA global interconnects**

Xiaoling Sun; Xu, S.; Jian Xu; Trouborst, P.;  
Electrical and Computer Engineering, 2001. Canadian Conference on  
Volume 2, 13-16 May 2001 Page(s):1251 - 1257 vol.2

IEEE CNF

**3. Testing Xilinx XC4000 configurable logic blocks with carry logic-modules**

Xiaoling Sun; Jian Xu; Trouborst, P.;  
Defect and Fault Tolerance in VLSI Systems, 2001. Proceedings. 2001 IEEE International Symposium on  
24-26 Oct. 2001 Page(s):221 - 229

IEEE CNF

**4. Novel technique for built-in self-test of FPGA interconnects**

Xiaoling Sun; Jian Xu; Ben Chan; Trouborst, P.;  
Test Conference, 2000. Proceedings. International  
3-5 Oct. 2000 Page(s):795 - 803

IEEE CNF

**5. BIST-based test and diagnosis of FPGA logic blocks**

Abramovici, M.; Stroud, C.E.;  
Very Large Scale Integration (VLSI) Systems, IEEE Transactions on  
Volume 9, Issue 1, Feb. 2001 Page(s):159 - 172

IEEE JNL

**6. Configuration self-test in FPGA-based reconfigurable systems**

Quddus, W.; Jas, A.; Touba, N.A.;  
Circuits and Systems, 1999. ISCAS '99. Proceedings of the 1999 IEEE International Symposium on  
Volume 1., 30 May-2 June 1999 Page(s):97 - 100 vol.1

IEEE CNF

**7. Selecting built-in self-test configurations for field programmable gate arrays**

Stroud, C.; Lee, E.; Konala, S.; Abramovici, M.;  
AUTOTESTCON '96, 'Test Technology and Commercialization'. Conference Record  
16-19 Sept. 1996 Page(s):29 - 35

IEEE CNF

**8. On-wafer photoconductive sampling of MMICs**

Huang, S.-L.L.; Chauchard, E.A.; Lee, C.H.; Hung, H.-L.A.; Lee, T.T.; Joseph, T.;  
Microwave Theory and Techniques, IEEE Transactions on  
Volume 40, Issue 12, Dec. 1992 Page(s):2312 - 2320

IEEE JNL

**9. Test scheduling with loop folding and its application to test configurations with accumulators**

Stroele, A.P.; Mayer, F.;  
Test Symposium, 1999. (ATS '99) Proceedings. Eighth Asian  
16-18 Nov. 1999 Page(s):101 - 106

**IEEE CNF****10. Test configuration minimization for the logic cells of SRAM-based FPGAs: a case study**

Renovell, M.; Portal, J.M.; Figueras, J.; Zorian, Y.;

Test Workshop 1999. Proceedings. European

25-28 May 1999 Page(s):146 - 151

**IEEE CNF****11. SRAM-based FPGA's: testing the LUT/RAM modules**

Renovell, M.; Portal, J.M.; Figueras, J.; Zorian, Y.;

Test Conference, 1998. Proceedings. International

18-23 Oct. 1998 Page(s):1102 - 1111

**IEEE CNF**

© Copyright 2006 IEEE – All Rights Reserved

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	31	((test testing) near2 (configuration)).clm. and BIOS	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/06 06:22
L2	14	((test testing) near2 (configuration)).clm. and BIOS and (chip IC)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/06 07:27
L3	26	((test testing verif\$3) with (chip IC (integrated adj circuit))) same (configuration adj set\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/06 07:29
L4	1751	((test testing) with configuration) and ((compare comparing compared comparison) near4 expect\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/06 08:46
L5	405	((test testing) with configuration) and ((compare comparing compared comparison) near4 expect\$4) and report	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/06 08:46
L6	270	((test testing) with configuration) and ((compare comparing compared comparison) near4 expect\$4) and report and difference	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/06 08:47
L7	183	((test testing) with configuration) and ((compare comparing compared comparison) near4 expect\$4) and report and difference	USPAT; IBM_TDB	OR	ON	2006/02/06 08:47
L8	5	(Wang and Jing-Rung).in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/06 08:59

S1	50	("5237690" "6287765" "6462998" "5659680" "5526364" "5793775" "5825700" "5950145" "6028798" "6307877" "6462584" "5671433" "5822610" "4244048" "6195775" "5021996" "5260946" "5717701" "5757820" "6158032" "6175529" "6239611" "4333142" "4833620" "4918691" "4961191" "5198758" "5228045" "5274648" "5323400" "5369643" "5513339" "5636163" "5661729" "5708601" "5781560" "5812472" "5838951" "5909453" "5912852" "5914902" "5995424" "6107821" "4283620" "4490673" "4597042" "4835704" "4860290" "4873669" "4940909").pn.	USPAT	OR	ON	2006/02/03 20:27
S2	16765	("5237690" "6287765" "6462998" "5659680" "5526364" "5793775" "5825700" "5950145" "6028798" "6307877" "6462584" "5671433" "5822610" "4244048" "6195775" "5021996" "5260946" "5717701" "5757820" "6158032" "6175529" "6239611" "4333142" "4833620" "4918691" "4961191" "5198758" "5228045" "5274648" "5323400" "5369643" "5513339" "5636163" "5661729" "5708601" "5781560" "5812472" "5838951" "5909453" "5912852" "5914902" "5995424" "6107821" "4283620" "4490673" "4597042" "4835704" "4860290" "4873669" "4940909").pn. test with configuration	USPAT	OR	ON	2006/02/03 20:28
S3	38	("5237690" "6287765" "6462998" "5659680" "5526364" "5793775" "5825700" "5950145" "6028798" "6307877" "6462584" "5671433" "5822610" "4244048" "6195775" "5021996" "5260946" "5717701" "5757820" "6158032" "6175529" "6239611" "4333142" "4833620" "4918691" "4961191" "5198758" "5228045" "5274648" "5323400" "5369643" "5513339" "5636163" "5661729" "5708601" "5781560" "5812472" "5838951" "5909453" "5912852" "5914902" "5995424" "6107821" "4283620" "4490673" "4597042" "4835704" "4860290" "4873669" "4940909").pn. and test with configuration	USPAT	OR	ON	2006/02/03 20:28

S4	38	("5237690" "6287765" "6462998" "5659680" "5526364" "5793775" "5825700" "5950145" "6028798" "6307877" "6462584" "5671433" "5822610" "4244048" "6195775" "5021996" "5260946" "5717701" "5757820" "6158032" "6175529" "6239611" "4333142" "4833620" "4918691" "4961191" "5198758" "5228045" "5274648" "5323400" "5369643" "5513339" "5636163" "5661729" "5708601" "5781560" "5812472" "5838951" "5909453" "5912852" "5914902" "5995424" "6107821" "4283620" "4490673" "4597042" "4835704" "4860290" "4873669" "4940909").pn. and (test with configuration)	USPAT	OR	ON	2006/02/03 20:28
S5	7	("5237690" "6287765" "6462998" "5659680" "5526364" "5793775" "5825700" "5950145" "6028798" "6307877" "6462584" "5671433" "5822610" "4244048" "6195775" "5021996" "5260946" "5717701" "5757820" "6158032" "6175529" "6239611" "4333142" "4833620" "4918691" "4961191" "5198758" "5228045" "5274648" "5323400" "5369643" "5513339" "5636163" "5661729" "5708601" "5781560" "5812472" "5838951" "5909453" "5912852" "5914902" "5995424" "6107821" "4283620" "4490673" "4597042" "4835704" "4860290" "4873669" "4940909").pn. and (test with configuration with set\$4)	USPAT	OR	ON	2006/02/03 20:30
S6	376	(test testing) near2 (configuration with set\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/03 20:31
S7	16	(test testing) near2 (configuration with set\$4) and BIOS	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/06 08:59
S8	3	((test testing) near2 (configuration with set\$4)).clm. and BIOS	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/06 06:22